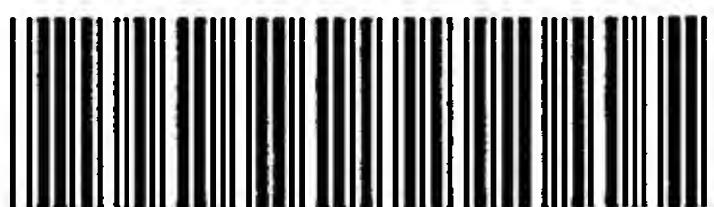


Search Notes**Application/Control No.**

10/708,835

Examiner

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Applicant(s)/Patent under Reexamination

BEENAU ET AL.

Art Unit

2635

SEARCHED

Class	Subclass	Date	Examiner
340	5.53	5/12/2006	NN
340	5.2	5/12/2006	NN
340	5.4+	5/12/2006	NN
340	5.52	5/12/2006	NN
340	5.6	5/12/2006	NN
340	5.8+	5/12/2006	NN
340	10.1	5/12/2006	NN
340	10.4-10.5	5/12/2006	NN
235	379	5/12/2006	NN
235	380	5/12/2006	NN
235	492	5/12/2006	NN
705	35,54,76	5/12/2006	NN
705	186,194	5/12/2006	NN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search: USPAT; US-PUB; EPO; JPO and Derwent. (UPDATED SEARCH).	5/12/2006	NN